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Nota di contenuto	Contents; Preface; List of contributors; 1 Fault diagnosis of linear and non-linear analogue circuits; 2 Symbolic function approaches for analogue fault diagnosis 37Stefano Manetti and Maria Cristina Piccirilli; 3 Neural-network-based approaches for analogue circuit faultdiagnosis; 4 Hierarchical/decomposition techniques for large-scale analoguediagnosis; 5 DFT and BIST techniques for analogue and mixed-signal test; 6 Design-for-testability of analogue filters; 7 Test of A/D converters: From converter characteristics to built-inself-test proposals; 8 Test of Sigma Delta converters 9 Phase-locked loop test methodologies: Current characterization and production test practices10 On-chip testing techniques for RF wireless transceiver systemsand components; 11 Tuning and calibration of analogue, mixed-signal and RF circuits; Index
Sommario/riassunto	This book provides a comprehensive discussion of automatic testing, diagnosis and tuning of analogue, mixed-signal and RF integrated circuits and systems in a single source.